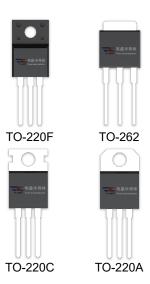


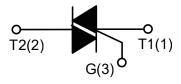
DESCRIPTION:

The BTA16-600B SCR series with the parallel resistor between Gate and Cathode are especially recommended for use on straight hair, igniter, anion generator, etc.



MAIN FEATURES

| Symbol | Value | Unit |
|------------------------------------|--------------|------|
| I _{T(RMS)} | 16 | Α |
| V _{DRM} /V _{RRM} | 600/800/1200 | V |



ABSOLUTE MAXIMUM RATINGS

| Р | arameter | Symbol | Value | Unit |
|--|---------------------------------------|---------------------|-----------------------|------------|
| Storage junction temperature range | | T _{stg} | -40-150 | $^{\circ}$ |
| Operating junction temperature range | | Tj | -40-125 | $^{\circ}$ |
| Repetitive peak of | f-state voltage (T _j =25℃) | V _{DRM} | 600/800/1200 | V |
| Repetitive peak reverse voltage (T _j =25℃) | | V _{RRM} | 600/800/1200 | V |
| Non repetitive surge peak Off-state voltage | | V _{DSM} | V _{DRM} +100 | V |
| Non repetitive peak reverse voltage | | V _{RSM} | V _{RRM} +100 | V |
| TO-220A(Ins)/ TO-220F(Ins) (T _C =75°C) TO-220A(Non-Ins)/ TO-220C (T _C =95°C) TO-262 (T _C =70°C) | | I _{T(RMS)} | 16 | А |
| Non repetitive surge peak on-state current (full cycle, F=50Hz) | | I _{TSM} | 160 | А |



| I ² t value for fusing (tp=10ms) | l ² t | 128 | A ² s |
|---|--------------------|-----|------------------|
| Critical rate of rise of on-state current $(I_G = 2 \times I_{GT})$ | dl/dt | 50 | A/µs |
| Peak gate current | I _{GM} | 4 | Α |
| Average gate power dissipation | P _{G(AV)} | 1 | W |
| Peak gate power | P _{GM} | 5 | W |

ELECTRICAL CHARACTERISTICS (T_j =25 $^{\circ}$ C unless otherwise specified)

3 Quadrants

| Symbol | Test Condition | Quadrant | | Value | | | | Unit |
|------------------|--|-------------|-------|-------|-----|-----|-----|-------|
| | | | | BW | CW | sw | TW | Offic |
| Ідт | V 40V D 000 | I - II -III | MAX | 50 | 35 | 10 | 5 | mA |
| V _G T | V _D =12V R _L =33Ω | I - II -III | MAX | 1.3 | | | | V |
| V _{GD} | $V_D = V_{DRM} T_j = 125$ °C $R_L = 3.3$ ΚΩ | I - II -III | MIN | 0.2 | | | V | |
| IL | I _G =1.2I _{GT} | I -III | MAX | 70 | 50 | 30 | 15 | mΛ |
| | | II | IVIAA | 80 | 60 | 40 | 20 | mA |
| Ін | I _T =100mA | | MAX | 60 | 40 | 25 | 15 | mA |
| dV/dt | V _D =2/3V _{DRM} Gate Open T _j =125℃ | | MIN | 1000 | 500 | 200 | 100 | V/µs |

4 Quadrants

| Symbol | Test Condition Quad | | Quadrant | Va | Unit | |
|------------------|--|-------------|----------|-----|------|-------|
| Symbol | rest Condition | Quaurant | | В | С | Ullit |
| lgт | | I - II -III | MAX | 50 | 25 | — mA |
| | V _D =12V R _L =33Ω | IV | | 70 | 50 | |
| V _G T | | ALL | MAX | 1.5 | | V |
| V _{GD} | $V_D = V_{DRM} T_j = 125^{\circ}C$ $R_L = 3.3 K\Omega$ | ALL | MIN | 0.2 | | V |
| lι | I _G =1.2I _{GT} | I -III-IV | MAX | 70 | 50 | m A |
| | | II | IVIAA | 100 | 80 | mA |
| Ін | I _T =100mA | | MAX | 60 | 40 | mA |
| dV/dt | V _D =2/3V _{DRM} Gate Open T _j =125℃ | | MIN | 500 | 200 | V/µs |



STATIC CHARACTERISTICS

| Cumbal | Parameter | | V | Unit | | |
|------------------|---|----------------------|-------|-------|--------|-------|
| Symbol | | | -600V | -800V | -1200V | Offic |
| V _{TM} | I _{TM} =22.5A tp=380μs | T _j =25℃ | 1.5 | | | V |
| I _{DRM} | V _D =V _{DRM} V _R =V _{RRM} | T _j =25℃ | 5 | 5 | 10 | μA |
| I _{RRM} | | T _j =125℃ | 1 | 1 | 2 | mA |

THERMAL RESISTANCES

| Symbol | Parameter | | Value | Unit |
|----------------------|----------------------|------------------------------|-------|------|
| R _{th(j-c)} | | TO-220A(Ins) | 2.1 | °C/W |
| | junction to case(AC) | TO-220A(Non-Ins)/ TO-220C | 1.2 | |
| | | TO-220F(Ins) | 2.3 | |
| | | TO-262 | 2.5 | |



FIG.1 Maximum power dissipation versus RMS on-state current

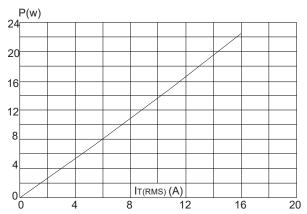


FIG.3: Surge peak on-state current versus number of cycles

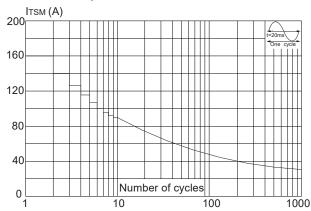


FIG.5: Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp<20ms, and corresponging value of I²t (dI/dt < 50A/µs)

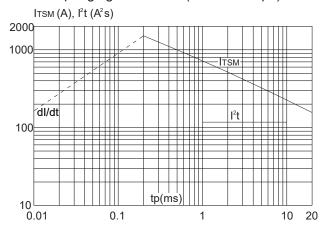


FIG.2: RMS on-state current versus case temperature



FIG.4: On-state characteristics (maximum values)

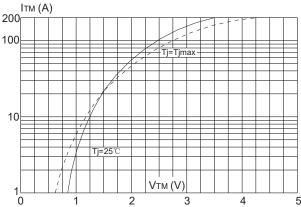


FIG.6: Relative variations of gate trigger current, holding current and latching current versus junction temperature

